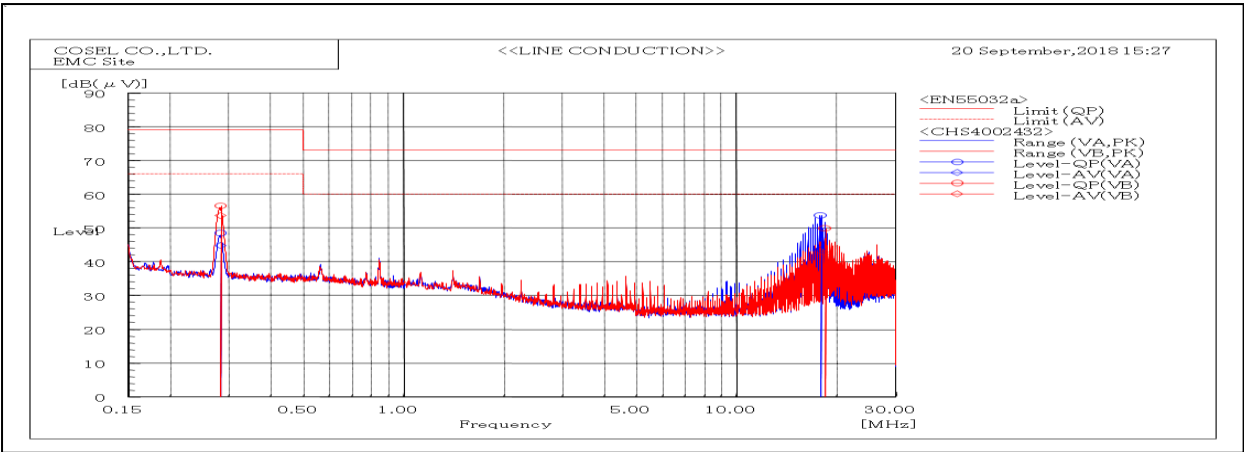
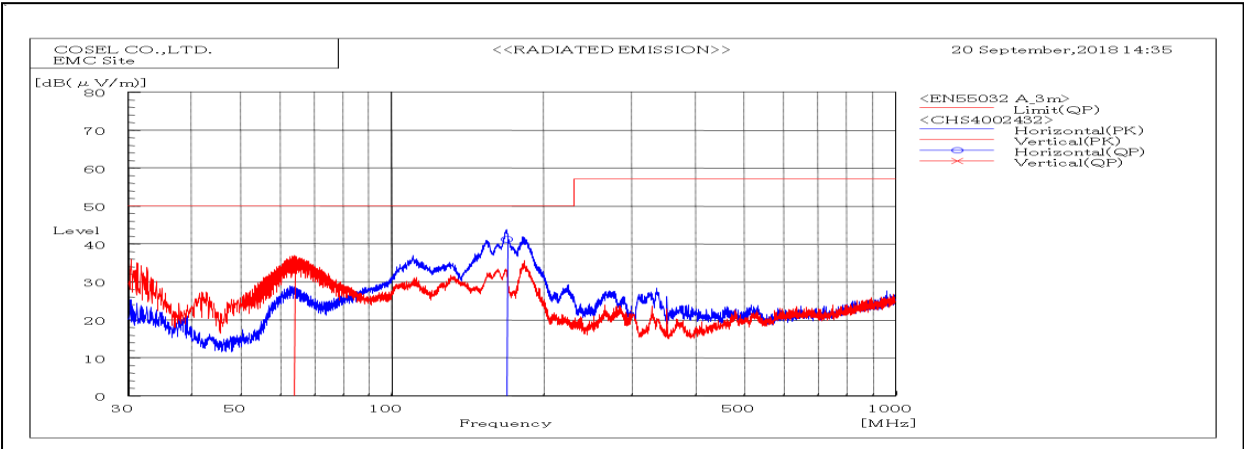


DATA SHEET		Date	27-Sep-18
Model	CHS4002432	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Nakagawa



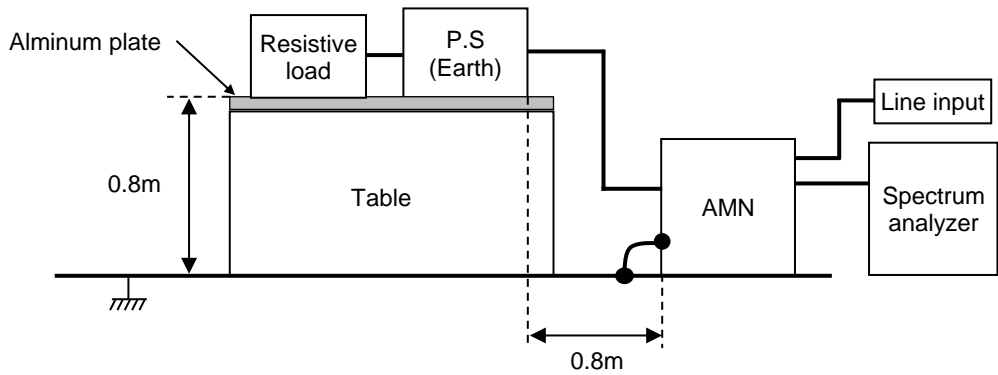
Frequency MHz	Line Phase	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.28335	VA	48.5	44.8	79	66	30.5	21.2	Pass	
0.2839	VB	56.6	53.7	79	66	22.4	12.3	Pass	
17.90295	VA	53.7	43.6	73	60	19.3	16.4	Pass	
18.43335	VB	49.9	42.6	73	60	23.1	17.4	Pass	



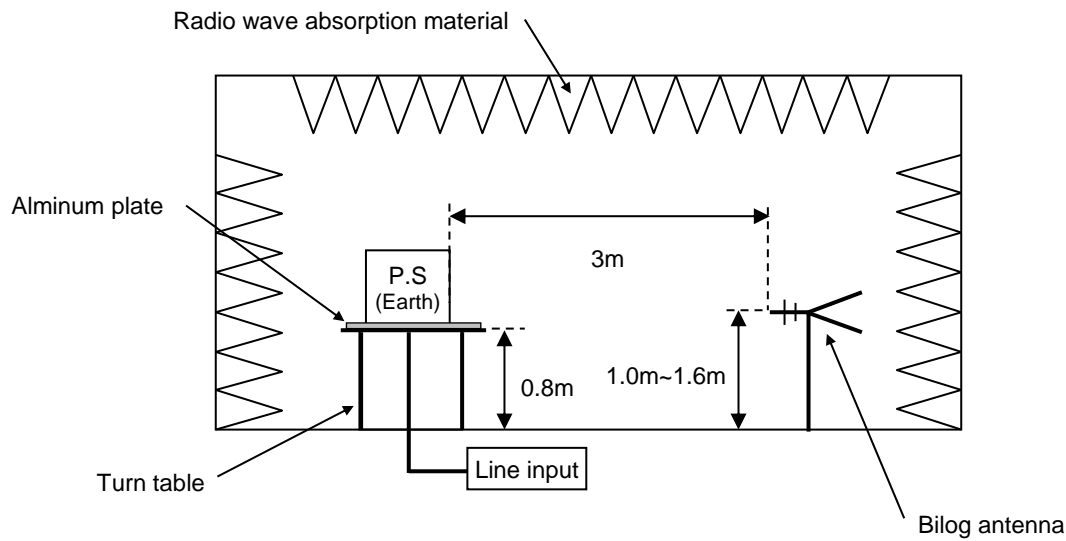
Frequency MHz	Polarization	Stability	Reading dB(uV)	Limit dB(uV/m)	Margin dB(uV/m)	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
64.208	V	Stable	34.6	50.0	15.4	Pass	103	94	
169.149	H	Stable	41.2	50.0	8.8	Pass	150	309	

DATA SHEET		Date	27-Sep-18
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Nakagawa

1. Line conduction



2. Radiated emission



Conditions

Test : EMI
Model Name : CHS40024□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

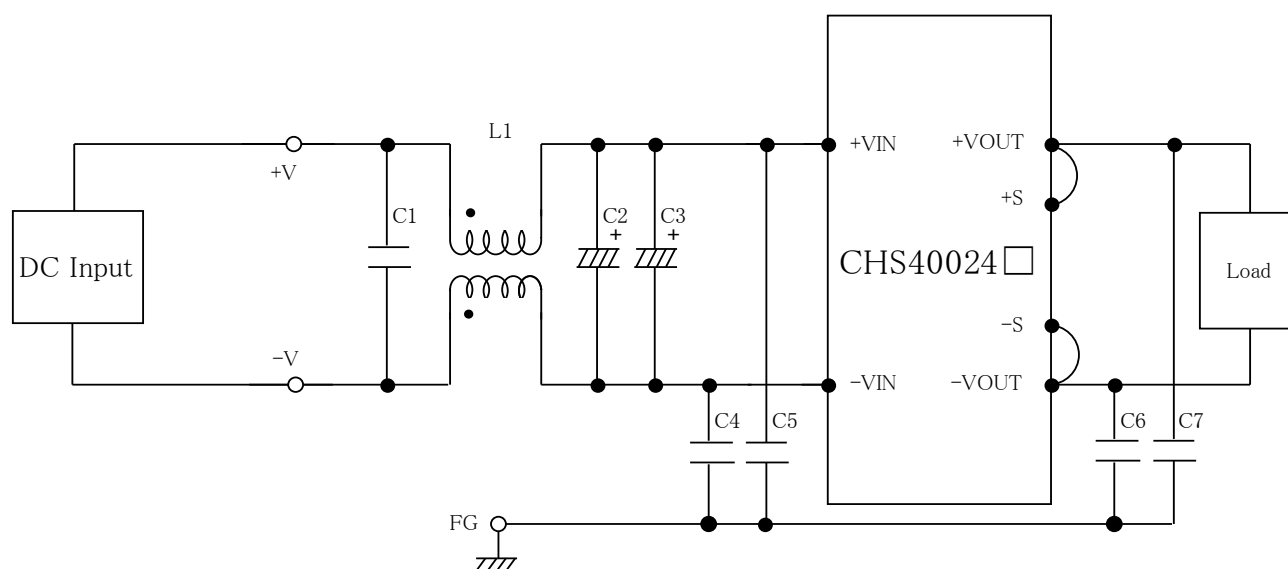


Fig.1 Testing circuitry

L1 : 1mH SC-30-100 (TOKIN)
C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
C2,C3 : 50V 330 μ F PWseries (nichicon)
C4,C5 : 630V 0.068 μ F FPD22J683J4 (NITSUKO)
C6,C7 : 630V 0.033 μ F FPD22J333J4 (NITSUKO)